Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/650,149	CHEN ET AL.	
Examiner	Art Unit	
William J. Deane	2614	

SEARCHED				
Class	Subclass	Date	Examiner	
379	211.02	1350107	n	
1	37			
	37 40			
	211.01			
	212.01			
	219			
b	21.02 19	V		
		•		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NO (INCLUDING SEARCH	TES I STRATEGY)
	DATE	EXMR
·		